

FEATURES

Bandwidth: 3.5 GHz
Input noise current density: 8 pA/√Hz
Optical sensitivity
 –22.0 dBm¹
 –20.4 dBm²
Differential transimpedance: 3700 V/A
Power dissipation: 80 mW
Differential output swing: 260 mV p-p
Input overload current: 5.6 mA p-p
On-chip RSSI function
Low frequency cutoff: 12 kHz
On-chip PD filter: R_F = 200 Ω, C_F = 20 pF
Die size: 0.7 mm × 1.2 mm

APPLICATIONS

4.25 Gbps optical receivers
GbE/FC optical receivers
SFF-8472-compliant receivers
PIN/APD-TIA receiver optical subassemblies

GENERAL DESCRIPTION

The [ADN2882](#) is a 3.3 V high gain SiGe transimpedance amplifier (TIA) which converts the small signal current of a photo detector to a large differential voltage output. The [ADN2882](#) features a typical 475 nA input-referred noise, enabling an optical sensitivity of –22 dBm (0.85 A/W PIN). With a bandwidth of 3.5 GHz, the [ADN2882](#) allows a data rate operation up to 4.25 Gbps. Typical power dissipation is 80 mW.

To facilitate the assembly in small form factor packages, such as TO-46 headers, the [ADN2882](#) provides an on-chip RC filter (200 Ω, 20 pF) and features a 12 kHz low frequency cutoff without using an external capacitor. An on-chip RSSI circuit, which generates a voltage proportional to the average photodiode current, is available for power monitoring and assembly alignment.

The [ADN2882](#) is available in die form. With a chip area of 1.2 mm × 0.7 mm, the TIA layout is optimized for TO-Can-based packages.

¹ Based on 1550 nm PIN, C_D = 0.5 ± 0.10 pF, responsivity = 0.85 A/W, ER = 9 dB, PRBS 2³¹ – 1 at 4.25 Gbps, BER < 10⁻¹².

² Calculated result based on an 850 nm PIN, C_D = 0.5 ± 0.15 pF, responsivity = 0.48 A/W, ER = 9 dB, at 4.25 Gbps, BER < 10⁻¹².

FUNCTIONAL BLOCK DIAGRAM

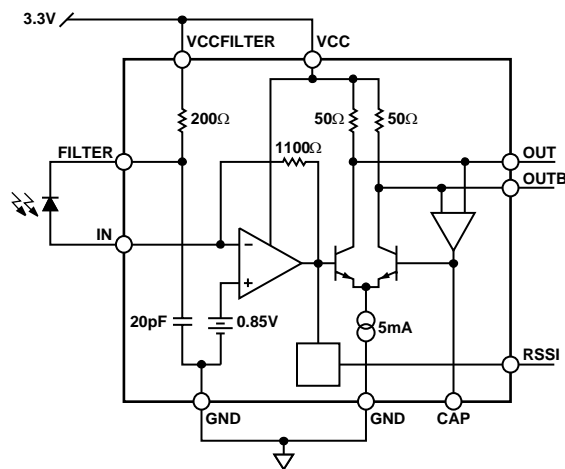


Figure 1.

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REVISION HISTORY

9/14—Rev. 0 to Rev. A

Changes to Figure 19.....	9
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Changes to Ordering Guide.....	12

6/05—Revision 0: Initial Version

SPECIFICATIONS

Minimum/maximum VCC = 3.3 V \pm 0.3 V, T_{AMBIENT} = -40°C to +95°C; typical VCC = 3.3 V, T_{AMBIENT} = 25°C, unless otherwise noted.

Table 1.

Parameter	Conditions	Min	Typ	Max	Unit
DYNAMIC PERFORMANCE					
Bandwidth (BW) ¹	-3 dB	2.9	3.5		GHz
Total Input Referred RMS Noise (I _{RMS})	C _D = 0.5 pF, 4.0 GHz low-pass filter		475	605	nA
Small Signal Transimpedance (Z _T) ¹	100 MHz, differential	2800	3700	4800	V/A
	100 MHz, single-ended	1400	1850	2400	V/A
Low Frequency Cutoff	I _{IN} = 20 μ A, CAP open		12		kHz
	I _{IN} = 500 μ A, CAP open		84		kHz
Output Return Loss	DC to 4.0 GHz, differential		-25		dB
Input Overload Current	ER = 10 dB	3.5	5.6		mA p-p
Maximum Differential Output Swing	I _{IN, P-P} = 2.0 mA	170	260	375	mV p-p
Output Data Transition Time	I _{IN, P-P} = 1.0 mA; 20% to 80% rise/fall time		46		ps
PSRR	I _{IN} = 0 mA, 1 MHz < frequency < 10 MHz		40		dB
Group Delay Variation	1.0 GHz to 4.0 GHz		\pm 12		ps
Transimpedance Ripple	50 MHz to 1.0 GHz, single-ended		0.5		dB
Deterministic Jitter	10 μ A < I _{IN, P-P} \leq 100 μ A, K28.5 @ 4.25 Gbps		8		ps p-p
	100 μ A < I _{IN, P-P} \leq 1.0 mA, K28.5 @ 4.25 Gbps		15		ps p-p
Linear Output Range	Differential output, <1 dB compression		190		mV p-p
Linear Input Current Range	Single-ended input, <1 dB compression		45		μ A p-p
DC PERFORMANCE					
Power Dissipation	I _{IN, AVE} = 0		80	110	mW
Input Voltage	Compliance voltage		0.85		V
Output Common-Mode Voltage	DC (50 Ω) terminated to VCC		VCC - 0.12		V
Output Impedance	Single-ended		50		Ω
PD Filter Resistance	R _F		200		Ω
PD Filter Capacitance	C _F		20		pF
RSSI Gain	I _{IN, AVE} = 5 μ A to 1 mA		0.83		V/mA
RSSI Offset	I _{IN, AVE} = 10 μ A		4.6		mV
RSSI Accuracy	5 μ A < I _{IN, P-P} \leq 20 μ A		\pm 9		%
	20 μ A < I _{IN, P-P} \leq 1 mA		\pm 3		%

¹ A signal current equivalent to I_{IN, P-P} = 10 μ A is applied to the TIA input. No input capacitor is applied.

ABSOLUTE MAXIMUM RATINGS

Table 2.

Parameter	Rating
Supply Voltage (VCC to GND)	5 V
Maximum Voltage to All Input and Output Signal Pins	VCC + 0.4 V
Minimum Voltage to All Input and Output Signal Pins	GND – 0.4 V
Maximum Input Current	10 mA
Storage Temperature Range	–65°C to +125°C
Operating Ambient Temperature Range	–40°C to +95°C
Maximum Junction Temperature	125°C
Die Attach Temperature (<30 sec)	410°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN LAYOUT AND FUNCTION DESCRIPTIONS

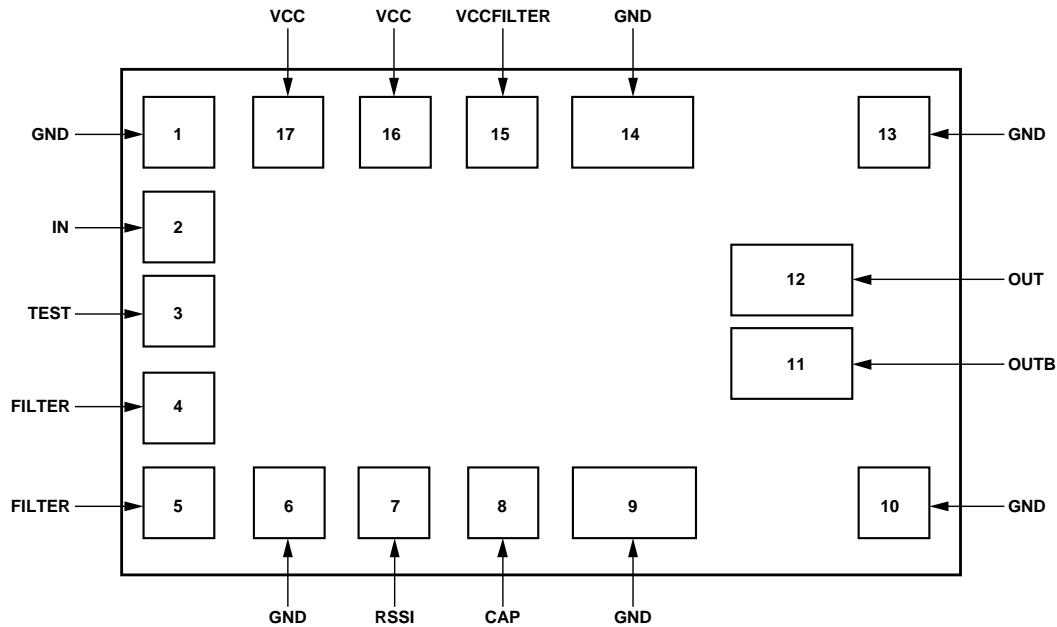


Figure 2. Pad Layout

Table 3. Pad Function Descriptions

Pad No.	Mnemonic	Pin Type ¹	Description
1	GND	P	Ground. (Input return.)
2	IN	AI	Current Input. Bond directly to a photodiode (PD) anode.
3	TEST	AI	Test Probe Pad. Do not connect.
4	FILTER	AO	Filter Output. Pad 4 and Pad 5 are metal connected. Optional bond to a PD cathode.
5	FILTER	AO	Filter Output. Pad 4 and Pad 5 are metal connected. Optional bond to a PD cathode.
6	GND	P	Ground.
7	RSSI	AO	Voltage Output. Provides average input current monitoring. Leave it open, if not used.
8	CAP	AI	Leave This Pin Open for Non-SONET Applications. For SONET applications, see Figure 10 and contact sales for assembly details.
9	GND	P	Ground. (Output return.)
10	GND	P	Ground. (Output return.)
11	OUTB	AO	Negative Output, CML, On-Chip 50 Ω Termination (AC or DC Termination).
12	OUT	AO	Positive Output, CML, On-Chip 50 Ω Termination (AC or DC Termination).
13	GND	P	Ground. (Output return.)
14	GND	P	Ground. (Output return.)
15	VCCFILTER	P	On-Chip Filter Supply. Connect to VCC to Enable On-Chip RC Filter (200 Ω , 20 pF). Leave it open, if not used.
16	VCC	P	3.3 V Power Supply. Place a 200 pF, RF decoupling capacitor close to the power pad to reduce the power noise.
17	VCC	P	3.3 V Power Supply. Place a 200 pF, RF decoupling capacitor close to the power pad to reduce the power noise.

¹ P = power; AI = analog input; and AO = analog output.

TYPICAL PERFORMANCE CHARACTERISTICS

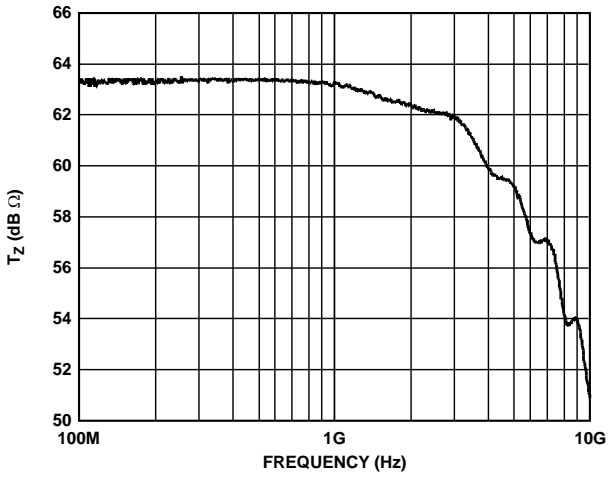


Figure 3. Single-Ended Transimpedance vs. Frequency

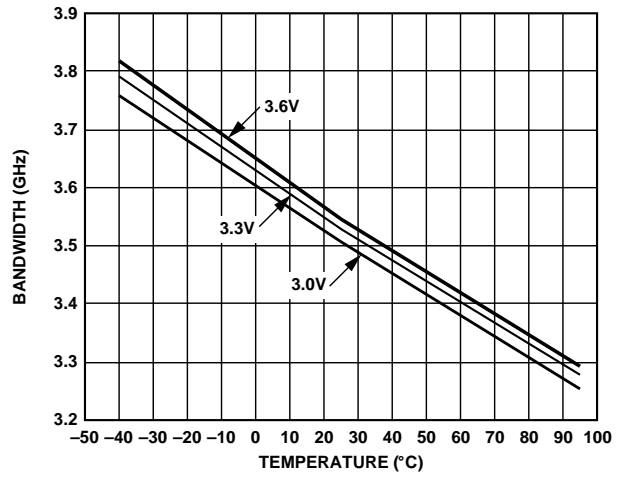


Figure 6. Bandwidth vs. VCC and Temperature

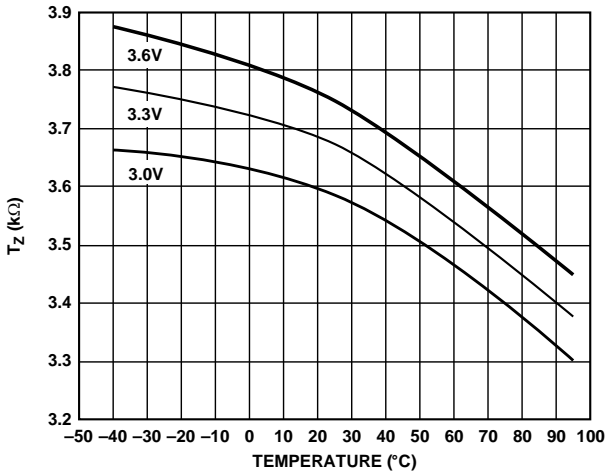


Figure 4. Differential Transimpedance vs. VCC and Temperature

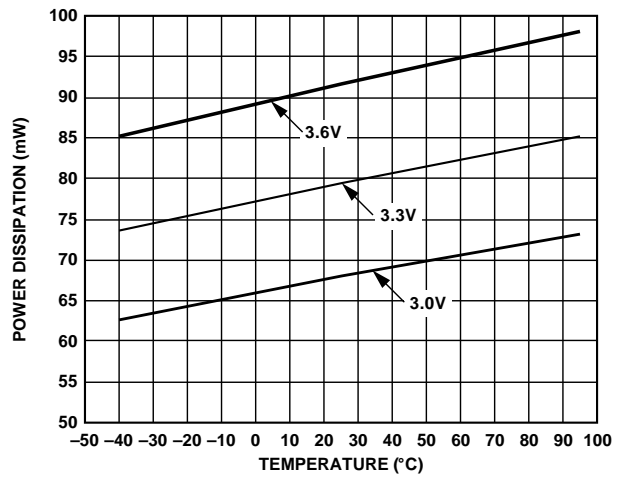


Figure 7. Power Dissipation vs. VCC and Temperature

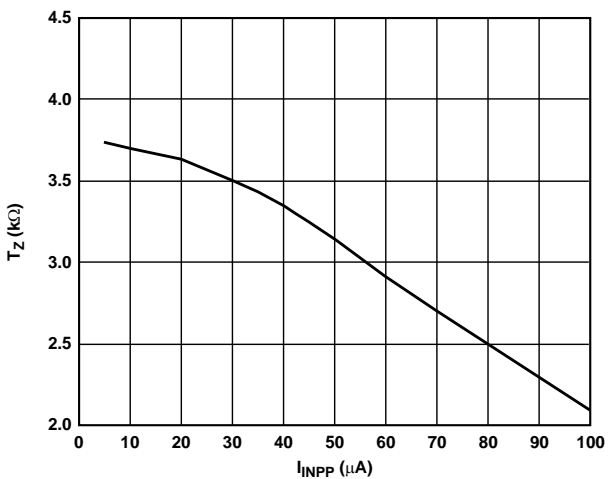


Figure 5. Differential Transimpedance vs. Input Current

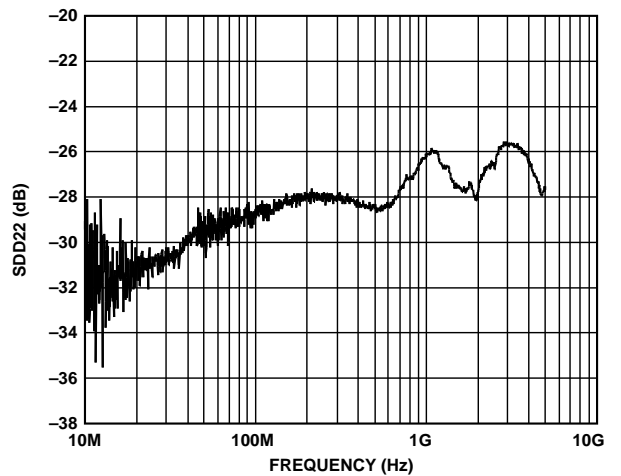


Figure 8. SDD22 vs. Frequency Up to 5 GHz, CAP = Open

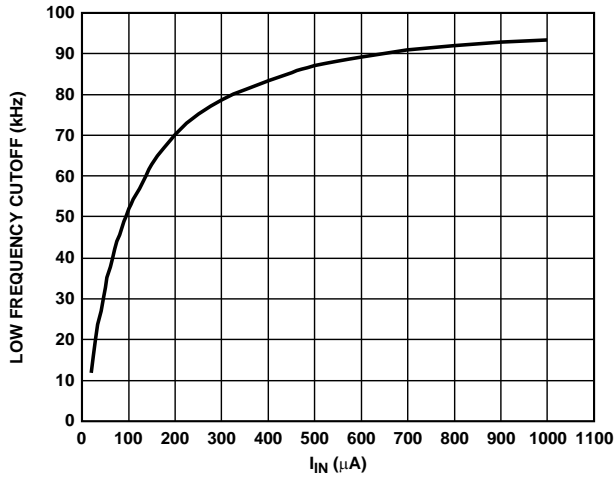


Figure 9. Low Frequency Cutoff vs. Input Current (CAP = OPEN)

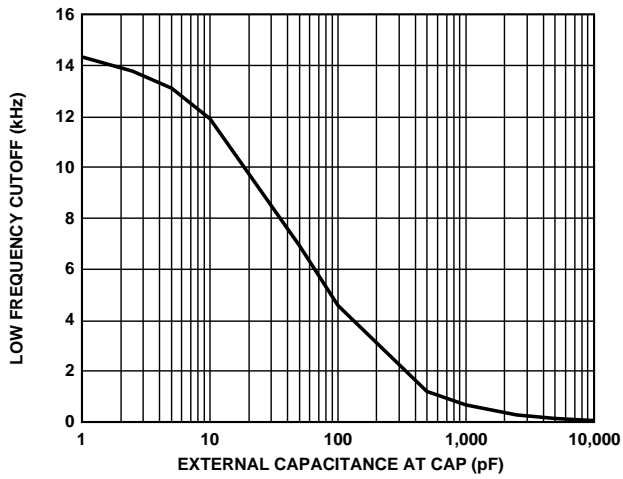


Figure 10. Low Frequency Cutoff vs. External Capacitance at CAP

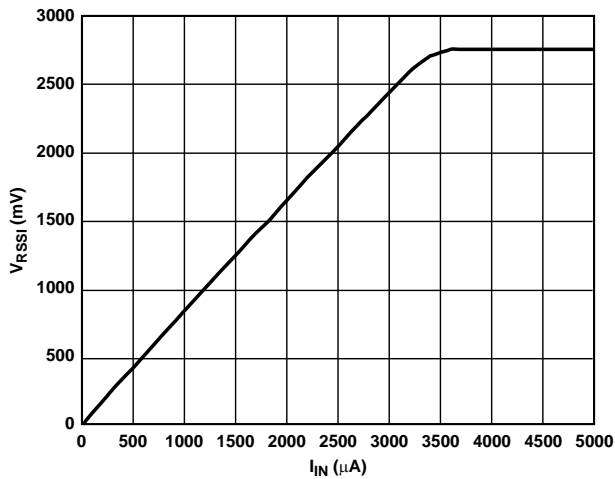


Figure 11. Full-Scale of RSSI Voltage Output vs. Input Current

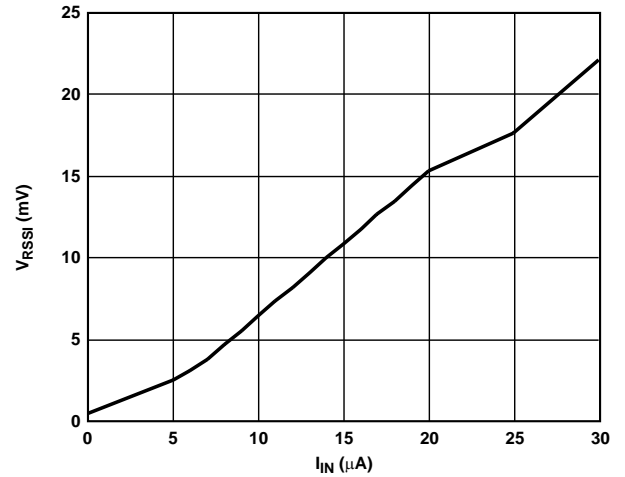


Figure 12. RSSI Voltage Output vs. Input Current (0 μ A to 30 μ A)

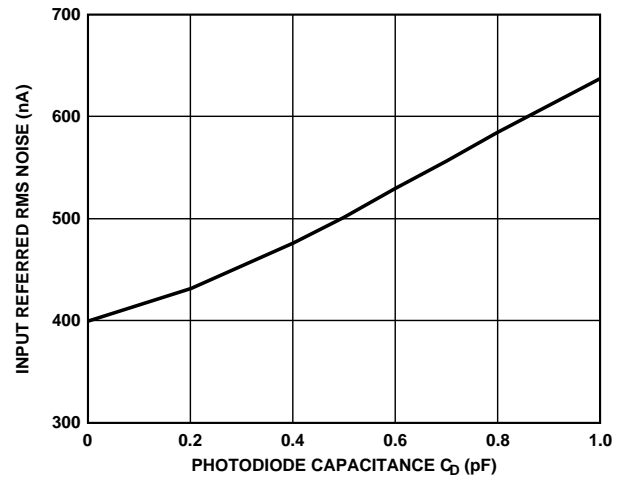


Figure 13. Input Referred Noise (DC to 4.0 GHz) vs. PD Capacitance

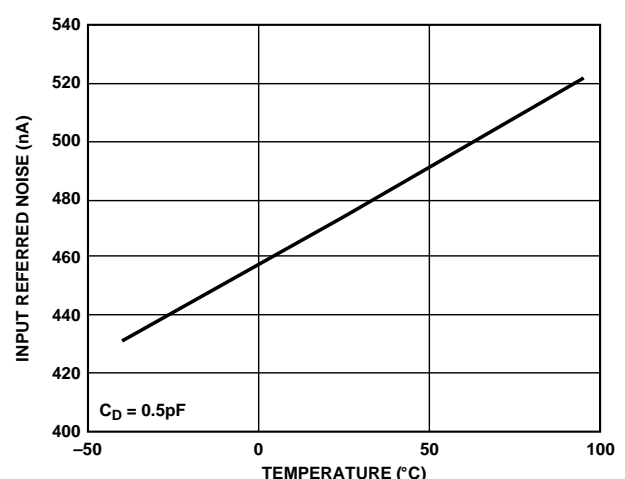
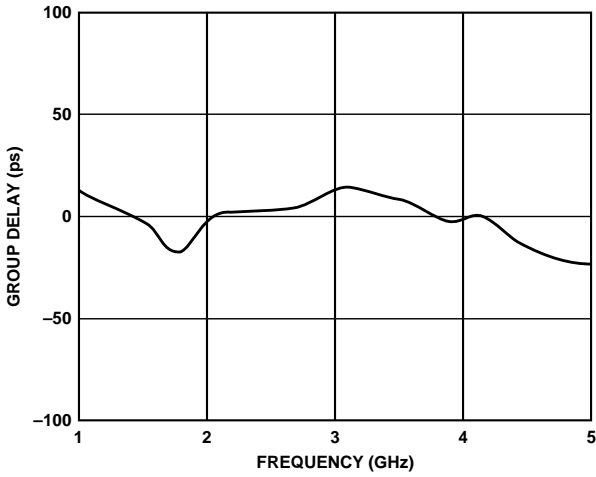
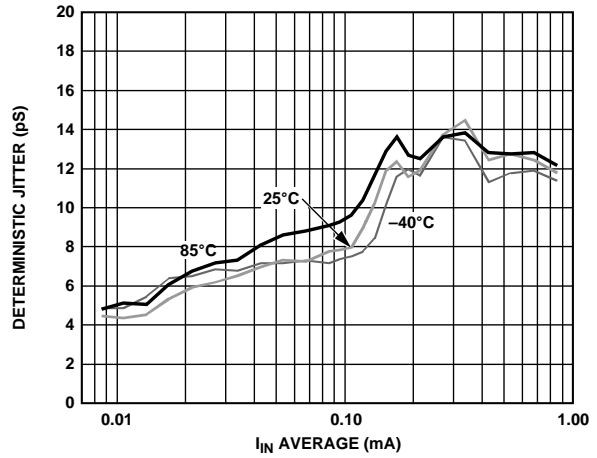


Figure 14. Input Referred Noise vs. Temperature



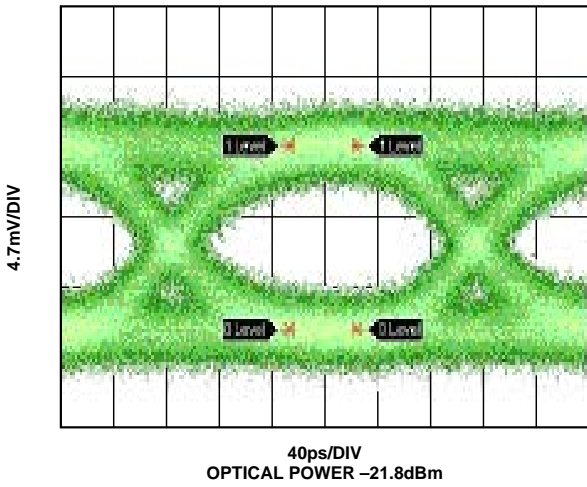
04946-018

Figure 15. Group Delay vs. Frequency



04946-026

Figure 17. Deterministic Jitter vs. Input Current (K28.5 @ 4.25 Gbps)

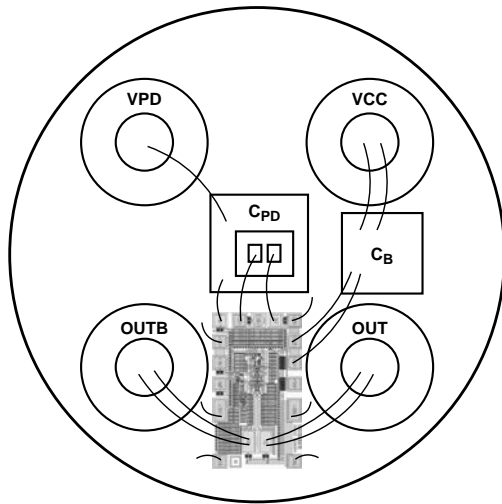


04946-019

Figure 16. Output Eye at 4.25 Gbps
(1550 nm PD with Responsivity = 0.85 A/W,
ER = 9 dB, PRBS $2^{31} - 1$, BER < 10^{-12})

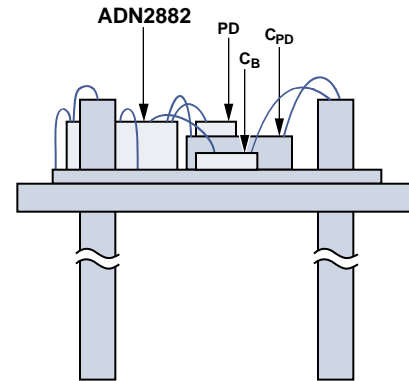
5-PIN TO-46 ASSEMBLY RECOMMENDATIONS

Contact sales for more details.



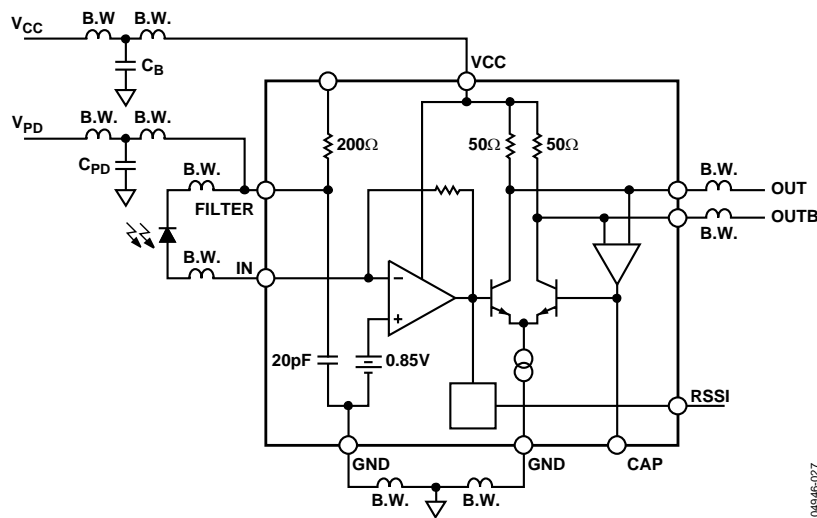
04946-003

Figure 18. 5-Pin TO-46 with External Photodiode Supply VPD



04946-031

Figure 19. Side View of the Assembly



04946-027

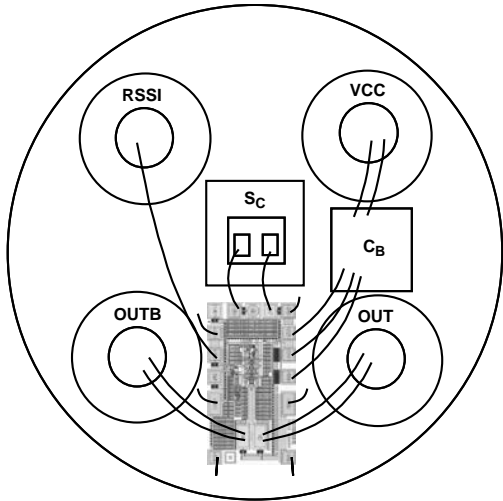
Figure 20. Equivalent Circuit of Assembly Including Bond Wires

Table 4. Bill of Materials (BOM)

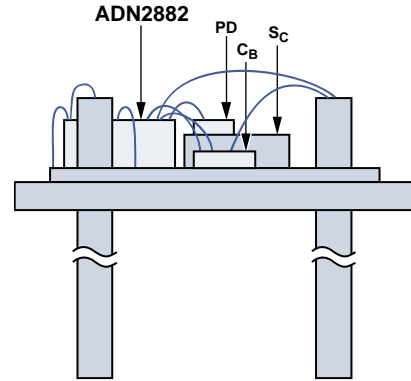
Component	Description
PD	1× vendor specific, 4.25 Gbps, photodiode
TIA	1× ADN2882 (0.7 mm × 1.2 mm), 4.25 Gbps, transimpedance amplifier
C _B	1× 200 pF, RF single-layer capacitor
C _{PD}	1× 560 pF, RF single-layer capacitor

Notes

- One mil thickness gold wire, ball bond recommended.
- Minimize all GND bond-wire lengths.
- Minimize IN, FILTER, OUT, and OUTB bond-wire lengths.
- Maintain symmetry in length and orientation between OUT and OUTB bond wires.
- Maintain symmetry between IN/FILTER and OUT/OUTB bond wires.



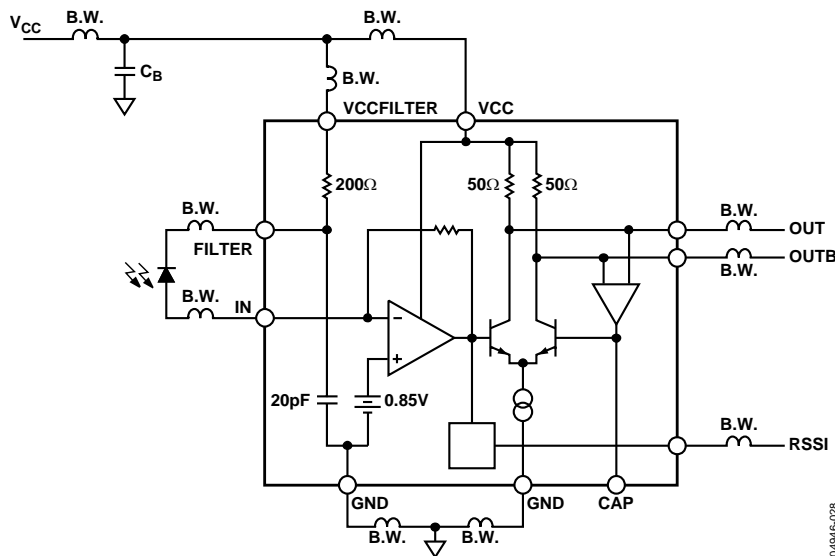
0-9346-023



0-9346-022

Figure 21. 5-Pin TO-46 with Internal PD Biasing and RSSI Output

Figure 22. Side View of the Assembly



0-9346-028

Figure 23. Equivalent Circuit of the Assembly Including Bond Wires

Table 5. Bill of Materials (BOM)

Component	Description
PD	1× vendor specific, 4.25 Gbps, photodiode
TIA	1× ADN2882 (0.7 mm × 1.2 mm), 4.25 Gbps, transimpedance amplifier
C _B	1× 200 pF, RF single-layer capacitor
S _C	1× ceramic standoff or 1× optional capacitor

Notes

- One mil thickness gold wire, ball bond recommended.
- Minimize all GND bond-wire lengths.
- Minimize IN, FILTER, OUT, and OUTB bond-wire lengths.
- Maintain symmetry in length and orientation between OUT and OUTB bond wires.
- Maintain symmetry between IN/FILTER and OUT/OUTB bond wires.

4-PIN TO-46 ASSEMBLY RECOMMENDATIONS

Contact sales for more details.

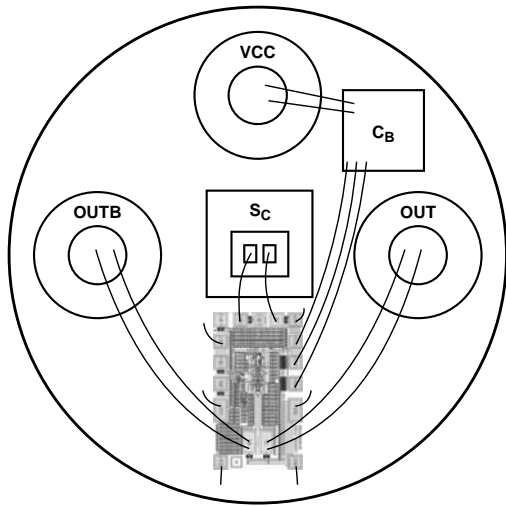


Figure 24. 4-Pin TO-46 with Internal PD Biasing

04946-004

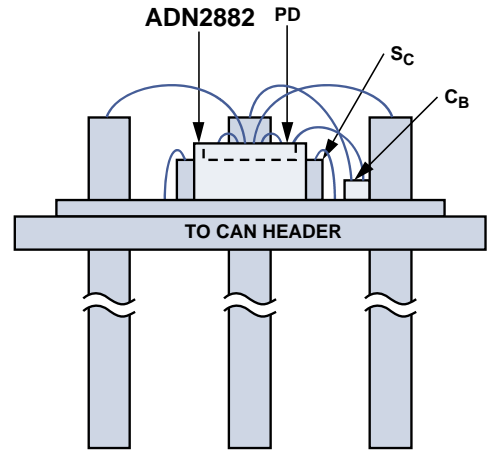


Figure 25. Side View of the Assembly

04946-030

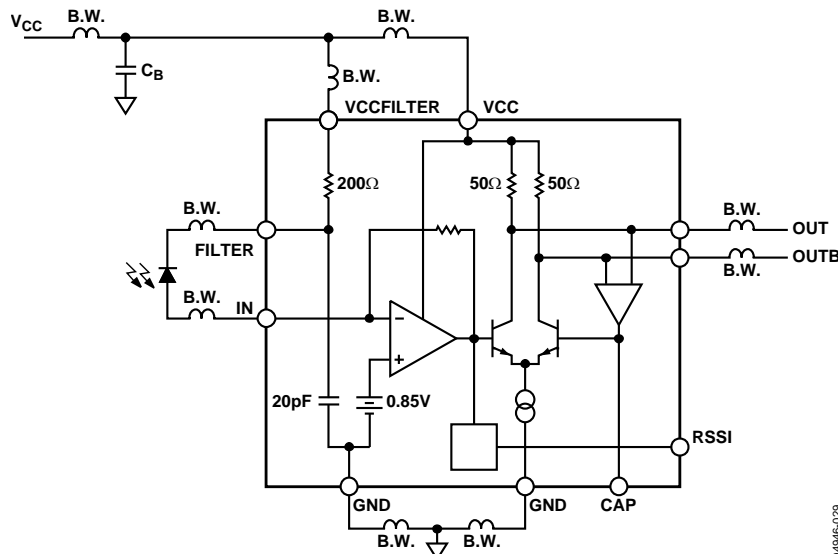


Figure 26. Equivalent Circuit of Assembly Including Bond Wires

04946-029

Table 6. Bill of Materials (BOM)

Component	Description
PD	1× vendor specific, 4.25 Gbps, photodiode
TIA	1× ADN2882 (0.7 mm × 1.2 mm), 4.25 Gbps, transimpedance amplifier
CB	1× 200 pF, RF single-layer capacitor
SC	1× ceramic standoff or 1× optional capacitor

Notes

One mil thickness gold wire, ball bond recommended.

Minimize all GND bond-wire lengths.

Minimize IN, FILTER, OUT, and OUTB bond-wire lengths.

Maintain symmetry in length and orientation between OUT and OUTB bond wires.

Maintain symmetry between IN/FILTER and OUT/OUTB bond wires.

OUTLINE DIMENSIONS

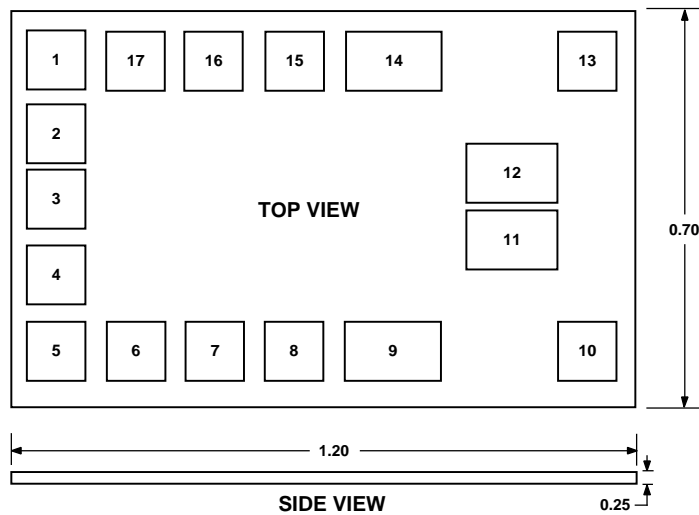


Figure 27. 17-Pad Bare Die Sales [CHIP]
C-17-1

Dimensions shown in millimeters

Table 7. Pad Coordinates

Pad No.	Mnemonic	X (μm)	Y (μm)
1	GND	-500	+260
2	IN	-500	+130
3	TEST	-500	+10
4	FILTER	-500	-120
5	FILTER	-500	-260
6	GND	-350	-260
7	RSSI	-200	-260
8	CAP	-50	-260
9	GND	+130	-260
10	GND	+500	-260
11	OUTB	+350	-60
12	OUT	+350	+60
13	GND	+500	+260
14	GND	+130	+260
15	VCCFILTER	-50	+260
16	VCC	-200	+260
17	VCC	-350	+260

DIE INFORMATION

Die Size

0.7 mm \times 1.2 mm (edge to edge, including 1 mil scribe)

Die Thickness

10 mils = 0.25 mm

Passivation Openings

0.075 mm \times 0.075 mm (Pad 1 to 8, 10, 13, and Pad 15 to 17)

0.144 mm \times 0.075 mm (Pad 9, 11, 12, and Pad 14)

Passivation Composition

5000 Å Si₃N₄ (top)

5000 Å SiO₂ (bottom)

Pad Composition

Al/1%Cu

Substrate Contact

To ground

ORDERING GUIDE

Model	Temperature	MOQ	Description ¹	Package Option
ADN2882ACHIPS	-40°C to +95°C	200	17-Pad Die Sales	C-17-1
ADN2882A-DF	-40°C to +95°C	5,704	Reconstituted die on 8" metal film frame	

¹ Contact Analog Devices, Inc., sales for more information on the film frame ADM2882A-DF.